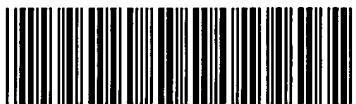


## **Search Notes**



**Application/Control No.**

10/500,210

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**Examiner**

Wen-Ying P. Chen

**Applicant(s)/Patent under  
Reexamination**

YAMASHITA ET AL.

## Art Unit

2871

**SEARCHED**

## **SEARCH NOTES (INCLUDING SEARCH STRATEGY)**

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner